

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/710,673	LEE ET AL.	
Examiner	Art Unit	
Hien Nauven	2816	

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	02.25.06	War		
EAST See attachmen				
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